



Reliability Data Report

Product Family R427

LTC4210 / LTC4211 / LTC4212 / LTC4214 /
LTC4230 / LTC4240 / LTC4241 / LTC4244 /
LTC4251 / LTC4252 / LTC4253 / LTC4350

Reliability Data Report

Report Number: R427

Report generated on: Tue Apr 05 13:03:03 PDT 2016

OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS (+125°C) ¹	No. of FAILURES ^{2,3}
SSOP/TSSOP	2348	0040	1243	1738	0
SOIC/MSOP	4834	0040	1507	3085	0
SOT	638	0531	1444	156	0
Totals	7,820	-	-	4,979	0

PRESSURE COOKER TEST AT 15 PSIG , +121 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HRS	No. of FAILURES
SSOP/TSSOP	5867	0027	1248	504	0
SOIC/MSOP	2541	0104	1418	151	0
QFN/DFN	150	0511	0741	34	0
SOT	3583	0143	1346	302	0
Totals	12,141	-	-	991	0

TEMP CYCLE FROM -65 TO 150 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP/TSSOP	1589	0027	1053	553	0
SOIC/MSOP	4196	9952	1418	545	0
QFN/DFN	150	0511	0741	55	0
SOT	2955	0143	1346	586	0
Totals	8,890	-	-	1,739	0

THERMAL SHOCK FROM -65 TO 150 DEG C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	No. of FAILURES
SSOP/TSSOP	1088	0129	1248	388	0
SOIC/MSOP	1989	0105	1418	278	0
QFN/DFN	150	0511	0741	55	0
SOT	2254	0143	1346	535	0
Totals	5,481	-	-	1,256	0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55 °C, 60% Confidence Level =2.38 FITS

(3) Mean Time Between Failure in Years = 47968.28

Note: 1 FIT = 1 Failure in One Billion Hours.

Note 2: HAST, Temp Cycle & Thermal Shock are subjected to J-STD-020 MSL1 Preconditioning